

Report No.: BTEK230919011AE002

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FCC ID: 2BC9U-W04CG

TEST REPORT

Application No.: BTEK230919011AE

Applicant: ZHONGSHAN SMART OPTOELECTRONICS TECHNOLOGY CO., LTD

Address of Applicant: 4501 and 4502B, Xinxing Science Park, No. 33 Xingteng Road, Tanzhou

Town, Zhongshan City, Guangdong Province, China

Manufacturer: ZHONGSHAN SMART OPTOELECTRONICS TECHNOLOGY CO., LTD

Address of Manufacturer: 4501 and 4502B, Xinxing Science Park, No. 33 Xingteng Road, Tanzhou

Town, Zhongshan City, Guangdong Province, China

Factory: ZHONGSHAN SMART OPTOELECTRONICS TECHNOLOGY CO., LTD

Address of Factory: 4501 and 4502B, Xinxing Science Park, No. 33 Xingteng Road, Tanzhou

Town, Zhongshan City, Guangdong Province, China

Equipment Under Test (EUT):

EUT Name: 16-line laser level

Model No.: W02CG, W03CG, W03DG, W04CG, W02CR, W03CR, W03DR, W04CR,

HP-W02CG, HP-W03CG, HP-W03DG, HP-W04CG, HP-W02CR, HP-

W03CR, HP-W03DR, HP-W04CR

Please refer to section 2 of this report which indicates which model was

actually tested and which were electrically identical.

Trade Mark: NA

Standard(s): 47 CFR Part 2 Subpart J Section 2.1093

Date of Receipt: 2023-09-19

Date of Test: 2023-09-20 to 2023-10-16

Date of Issue: 2023-10-16

Test Result: Pass*

Damon Su

EMC Laboratory Manager

ShenZhen BANTEK Testing Co.,Ltd.

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^{*} In the configuration tested, the EUT complied with the standards specified above.



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Revision Record					
Version Chapter		Date	Modifier	Remark	
01		2023-10-16		Original	
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		100			

Authorized for issue by		3 6 11
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	Carl Yang /Project Engineer	
	leans Tan	0 0
	keven lan.	
(((*15)	Keven Tan /Reviewer	- 1

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3 General Information

3.1 Details of E.U.T.

Power supply: The EUT received DC 11.1V by rechargeable Li-ion Battery(2600mAh) and

recharged by usb port.

Cable(s):

Frequency Range: 2402MHz to 2480MHz

Bluetooth Version: version 5.0 Modulation Type: GFSK Number of Channels: 40

Antenna Type: PCB Antenna Antenna Gain: -0.58dBi

Remark: The information in this section is provided by the applicant or manufacturer, BANTEK is not liable to the accuracy, suitability, reliability or/and integrity of the information.

3.2 Description of Support Units

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Description	Manufacturer	Model No.	Serial No.	
	0 0		<u></u>	
The FLIT has been tested as an independent unit				

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3.3 Test Location

All tests were performed at:

Shenzhen BANTEK Testing Co., Ltd.,

A5&A6, Building B1&B2, No.45 Gangtou Road, Bogang Community, Shajing Street, Bao'an District,

Shenzhen, Guangdong, China 518103

Tel:0755-2334 4200 Fax: 0755-2334 4200

FCC Registration Number: 264293 Designation Number: CN1356 No tests were sub-contracted.

3.4 Deviation from Standards

None

3.5 Abnormalities from Standard Conditions

None

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4 Test Requirement

KDB447498 D01 General RF Exposure Guidance v06, Clause 4.3.1(a)

[(max. power of channel, including tune-up tolerance, mW) / (min. test separation distance, mm)] • $[\sqrt{f(GHz)}] \le 3.0$

Where

- -f(GHz) is the RF channel transmit frequency in GHz
- -Power and distance are rounded to the nearest mW and mm before calculation
- -The test exclusions are applicable only when the minimum test separation distance is \leq 50 mm, and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm according to 4.1 f) is applied to determine SAR test exclusion.

4.1Assessment Result

Not Applicable

Туре	Frequency (MHz)	Conducted Power (dBm)	Maximum Tune-up (dBm)	Calculating data	Limit	Result
BLE	2402	1.81	2	0.49	3.0	Pass

Note: The exposure evaluation safety distance is 5mm.

- End of the Report -

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